

**Notice of References Cited**

Application/Control No.

10/728,518

Applicant(s)/Patent Under  
Reexamination  
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Examiner

Richard Pantoliano Jr

Art Unit

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Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,224,215	06-1993	Disbrow, John R.	709/234
*	B	US-6,058,389	05-2000	Chandra et al.	707/1
*	C	US-6,609,158	08-2003	Nevarez et al.	719/316
*	D	US-6,625,117	09-2003	Chen et al.	370/227
*	E	US-6,704,767	03-2004	Simmons et al.	718/104
*	F	US-6,934,247	08-2005	Bhattal et al.	370/216
*	G	US-6,976,260	12-2005	Ault et al.	719/314
*	H	US-7,111,063	09-2006	Clark et al.	709/225
*	I	US-7,136,868	11-2006	Sonkin et al.	707/102
*	J	US-7,159,221	01-2007	Willen et al.	718/104
*	K	US-2003/0112802	06-2003	Ono et al.	370/389
*	L	US-2004/0054896	03-2004	Himmel et al.	713/167
*	M	US-2005/0086237	04-2005	Monnie et al.	707/100

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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